PCNI	Numb	er:		202	231211001.1			PCN	N Date: December 12, 202		December 12, 2023	
Title:		Qualific	ation c	of RF	AB as a	ın a	dditional Fab s	ite opti	ion ar	nd BC	OM/A	ssembly Options for
· icic i		select d	evices	;								
Custo	omer (Contact	:		Chang	e M	lanagement Te	am	Dep	t:		Quality Services
Proposed 1 st Ship Date: Mar			Mar 1	0, 2	2024	Sample requests accepted until:			Jan 11, 2024*			
*Sam	iple re	equests	recei	ved	after J	lan	11, 2024 will	not be	sup	orte	ed.	
Chan	ge Ty	pe:										
\boxtimes	Asse	mbly Site	9			\boxtimes	Design				Wafer Bump Material	
\boxtimes	Asse	mbly Pro	cess				Data Sheet				Wafer Bump Process	
Assembly Materials					Part number change			X	Wafer Fab Site			
☐ Mechanical Specification						Test Site			X	Wafer Fab Material		
□ Packing/Shipping/Labeling				ng		Test Process			\boxtimes	Wafer Fab Process		
							PCN Detai	ls				

Texas Instruments is pleased to announce the qualification of its RFAB fabrication facility as an additional Wafer Fab option in addition to BOM/Assembly site options for the devices listed below.

Cı	ırrent Fab Site	•	Additional Fab site			
Current Fab Site	Process	Wafer Diameter	Additional Fab site	Process	Wafer Diameter	
FR-BIP-1	BCB8	300mm	FFAB	LBC9	300mm	

The die was also changed as a result of the process change.

Group 1 BOM Table:

Description of Change:

	Current	Additional
Bond wire composition, diameter diameter	Cu, 1.0 mil	Cu, 0.8 mil

Group 2 BOM Table:

	ASESH	HNA	UTL2	HFTF
Bond wire composition, diameter diameter	Au, 1.0 mil	Au, 1.0 mil	Au, 1.0 mil	Cu, 0.8 mil
Mount Compund	SID#EY1000063	SID#400180	SID#PZ001	SID#A-18
Mold Compound	SID#EN2000763	SID#450179	SID#CZ0094	SID#R-30
Lead finish	NiPdAu	NiPdAu	NiPdAu	Matte Sn

Upon expiry of this PCN TI will combine lead free solutions in a single <u>standard part number</u>, for the device in group 2. For example; <u>LMV393IDGKR</u> – can ship with both Matte Sn and NiPdAu.

Example:

- Customer order for 7500 units of LMV393IDGKR with 2500 units SPQ (Standard Pack Quantity per Reel).
- TI can satisfy the above order in one of the following ways.
 - I. 3 Reels of NiPdAu finish.
 - II. 3 Reels of Matte Sn finish
 - III. 2 Reels of Matte Sn and 1 reel of NiPdAu finish.
 - IV. 2 Reels of NiPdAu and 1 reel of Matte Sn finish.

Reason for Change:

Supply continuity

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Impact on Environmental Ratings

Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings.

RoHS	REACH	Green Status	IEC 62474
☑ No Change	⊠ No Change	⊠ No Change	⊠ No Change

Changes to product identification resulting from this PCN:

Fab Site Information:

Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
FR-BIP-1	TID	DEU	Freising
RFAB	RFB	USA	Richardson

Assembly Site Information:

Assembly Site	Assembly Site Origin (22L)	Assembly Country Code (23L)	Assembly City	
HNA	HNT	THA	Ayutthaya	
UTL2	NS2	THA	Bangpakong, Chachoengsao	
ASESH	ASH	CHN	Shanghai	
HFTF	HFT	CHN	Hefei	

Die Rev:

Current	New
Die Rev [2P]	Die Rev [2P]

Sample product shipping label (not actual product label):

TEXAS INSTRUMENTS MADE IN: Malaysia 2DC: 2Q;

MSL 2 /260C/1 YEAR SEAL DT MSL 1 /235C/UNLIM 03/29/04

OPT: ITEM:

TTEM: 5A (L)TO:3750



(1P) SN74LS07NSR (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483SI2

(2P) REV: (2P) REV: (V) 9933317 (20L) CSO: SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACO: MYS

Product Affected:

Group 1 Device List:

LMV339IDR

Group 2 Device List:

LMV393IDGKR

TI Information Selective Disclosure

Qualification Report

LMV339IDR Design and Process Change Approve Date 30-AUGUST -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	#	Test Name	Condition	Duration	Qual Device: <u>LMV339IDR</u>	QBS Reference: TLV1805QDBVRQ1	QBS Reference: SN74HCS74QDRQ1	QBS Reference: <u>TLV9034QDRQ1</u>
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	3/231/0	1/77/0
UHAST	А3	Unbiased HAST	130C/85%RH	96 Hours	-	-	3/231/0	1/77/0
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	3/231/0	1/77/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	3/135/0	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	1/77/0
HTOL	B1	Life Test	125C	1000 Hours	-	3/231/0	1/77/0	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	1/77/0
ESD	E2	ESD CDM	-	1000 Volts	1/3/0	-	-	-
ESD	E2	ESD HBM	-	2000 Volts	1/3/0	-	-	-
LU	E4	Latch-Up	Per JESD78	-	1/3/0	-	-	-
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	-	-	-

ESD	E2	ESD HBM	-	2000 Volts	1/3/0	-	-	-
LU	E4	Latch-Up	Per JESD78	-	1/3/0	-	-	-
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	-	-	-

- · QBS: Qual By Similarity
- Qual Device LMV339IDR is qualified at MSL1 260C
- . Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47:-55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

TI Qualification ID: R-CHG-2307-053

Qualification Report

LMV393IDGKR Refresh to TLV9022 Die and AT site. Approve Date 07-JULY -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	#	Test Name	Condition	Duration	Qual Device: LMV393IDGKR	QBS Reference: LM5008MM/NOPB	QBS Reference: TMP1826DGKR	QBS Reference: TLV9032QDGKRQ1	QBS Reference: TLV9022QDGKRQ1
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	3/231/0	1/77/0	1/77/0	1/77/0
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	-	3/231/0	1/77/0	1/77/0	1/77/0
тс	A4	Temperature Cycle	-55C/150C	700 Cycles	-	-	1/77/0	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	3/231/0	-	1/77/0	1/77/0
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	3/231/0	1/77/0	-	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	1/77/0	1/77/0
HTOL	B1	Life Test	150C	300 Hours	-	-	1/77/0	1/77/0	1/77/0
WBP	C2	Bond Pull	76 Wires, 3 units min	Wires	-	3/228/0	-	-	-
ESD	E2	ESD CDM	-	1500 Volts	1/3/0	-	-	-	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	-	-	-	1/3/0
LU	E4	Latch-Up	Per JESD78	-	-	-	-	-	1/6/0
FTY	E6	Final Test Yield	-	-	1/1/0	-	-	-	-

- · QBS: Qual By Similarity
- Qual Device LMV393IDGKR is qualified at MSL1 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

TI Qualification ID: R-CHG-2305-001

For questions regarding this notice, e-mails can be sent to the Change Management team or your local Field Sales Representative.

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